


<b>Search Notes</b>  	<b>Application/Control No.</b>  10540190	<b>Applicant(s)/Patent Under Reexamination</b>  TAN ET AL.
	<b>Examiner</b>  Stork, Kyle R	<b>Art Unit</b>  2178

SEARCHED			
Class	Subclass	Date	Examiner
715	513, 517, 523, 530	11/20/07	<i>Q</i>

SEARCH NOTES		
Search Notes	Date	Examiner
Update EAST Search (USPat, USPG-Pub)	11/20/07	<i>Q</i>
NPL Search (IEEE, ACM, Google)	11/20/07	<i>Q</i>

INTERFERENCE SEARCH			
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